# MULTI LAYER DEFECTS CALCULATION METHOD AND SYSTEM


## ABSTRACT

A method for multi-layer defects calculation, the method comprising obtaining raw defect count data representative of each single layer; deriving a cumulative probability for a non-zero defect event from the raw defect count data; deriving an average defect count for the non-zero defect event based on the raw defect count data; and calculating a multi-layer defect count value utilising a binomial distribution probability mass function based on the non-zero defect event and a zero defect event.


**FIG. 2**



*162162*



*G00002*